

FATENT, CON 11/25/02

## <u>IN THE UNITED STATES PATENT AND TRADEMARK OFFICE</u>

In re Application of:		Examiner:	Donghee Kango
	Ali Keshavarzi et al.	Art Unit:	2811 Yoru
Application No.: 09/469,406 ) Filed: December 22, 1999 )		I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to the Commissioner for Patents, Washington, D.C. 20231on:	
For:	DECOUPLING CAPACITORS FOR THIN ) GATE OXIDES )	Date of Deposit  Annie Pearson  Name of Person Mailing Correspondence	
: .		Anni	Pase 11/13/02

Commissioner for Patents Washington, D.C. 20231

## RESPONSE

Sir:

This is in response to the Office action dated August 13, 2002. Reconsideration of the application is requested. The claims are not amended in this response.

## ENTIRE SET OF PENDING CLAIMS (Clean version)

- 29. A die, comprising:
- a first conductor carrying a power supply voltage;
- a second conductor carrying a ground voltage; and
- a semiconductor <u>decoupling capacitor</u> to provide decoupling capacitance between the first and second conductors, the semiconductor decoupling capacitor including:
  - (a) a gate electrode coupled to the first conductor to receive the power supply voltage,
  - (b) a diffusion coupled to the second conductor to receive the ground voltage, and
  - (c) a body to receive the ground voltage through the diffusion, the semiconductor decoupling capacitor thereby being in depletion mode.
- F5.5 (30) The die of claim 29, wherein gate electrode is p-type and the diffusion and the